



PHASICS
The phase control company

SID4 eSWIR

HIGH RESOLUTION EXTENDED SWIR WAVEFRONT SENSOR

The SID4 eSWIR wavefront sensor integrates PHASICS patented technology with a T2SL detector. Thanks to its high spatial resolution and great sensitivity, it offers accurate wave front measurement over the extended SWIR range from 0.9 to 2.35 μm .

SID4 eSWIR is an innovative solution for testing SWIR sources and lenses used in optical communications, inspection instruments or night vision in military and surveillance devices. It provides both MTF and aberrations in one single shot.

APPLICATIONS: [Free-Space Optical Communication](#) | [Defense & Security](#) | [Aerospace](#)

SPECIFICATIONS

Wavelength range	0.9 - 2.35 μm
Aperture dimensions	9.6 x 7.68 mm ²
Phase spatial resolution	120 μm
Phase & Intensity sampling	80 x 64
Resolution (Phase)	<6 nm RMS*
Accuracy	<40 nm RMS*
Real-time processing frequency	10 Hz (full resolution)
Interface	USB 2.0
Dimensions	90 x 115 x 120 mm
Weight	~ 1.8 kg

** for coherent sources*